Laterally coupled dual-grating distributed feedback lasers for generating mode-beat terahertz signals

Lianping Hou,1,* Mohsin Haji,2 Iain Eddie,3 Hongliang Zhu,4 and John H. Marsh1

1School of Engineering, University of Glasgow, Glasgow G12 8LT, UK
2National Physical Laboratory, Teddington, Middlesex TW11 0LW, UK
3CST Global Ltd., 4 Stanley Blvd., Blantyre, Glasgow G72 0BN, UK
4Institute of Semiconductors, No. A35, East Qinghua Road, Haidian District, Beijing 1000083, China
*Corresponding author: lianping.hou@glasgow.ac.uk

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We present a laterally coupled dual wavelength 1.56/1.57-μm AlGanAs/InP DFB laser, which, by introducing two different grating periods on each sidewall, emits two longitudinal modes simultaneously within the same cavity at a frequency separation of 0.82 THz. The beating signal is stabilized by nonlinear four-wave mixing in an electro-absorption modulator (EAM), located within a monolithically integrated resonant cavity. A stable 0.82-THz beating signal was observed over a wide range of bias parameters in terms of drive currents and bias to the DFB and EAM sections. © 2014 Optical Society of America

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Terahertz (THz) radiation is of increasing importance for a variety of new applications, such as medical imaging, remote sensing, and THz communications [1,2]. One of the techniques used to generate optical THz signals is by photomixing beams from two different distributed feedback (DFB) lasers [3,4], or alternatively using an extended cavity configuration [5]. Dual-mode lasers (DMLs) utilizing integrated distributed Bragg reflectors (DBRs) or DFB laser cavities, have also been used [6,7]. A much simpler DML source for pumping, capable of uncooled operation and with a simple device structure is strongly desired. Among the various reported DML configurations, simultaneous emission of two longitudinal modes within the same cavity is very appealing because the device is compact, gives a stable beat frequency with high spectral quality, can be manufactured at low cost, and is straightforward to package [8].

DMLs operating in the 1.5-μm telecommunications window for silica fiber are most desirable. At this wavelength, a plethora of components has been developed to modulate, control, and manipulate optical signals, and erbium-doped fiber amplifiers (EDFAs) can be used to increase the signal power to hundreds of watts if required.

Here we report, for the first time, a 1.56-μm DML with two longitudinal modes lasing simultaneously within the same cavity separated by 0.82 THz. Both modes are affected by much the same electrical, thermal, and mechanical fluctuations, also known as the common-mode-noise rejection effects [3]. The frequency difference between the modes is determined essentially by each side of the laterally coupled grating structures, and crucially not by the ambient temperature or injection current (of course, a small difference frequency shift will appear due to fluctuations of temperature and injection current). An additional resonator, containing an electro-absorption modulator (EAM) in which four-wave mixing (FWM) takes place, locks the phase of the two optical signals. In contrast to the complex fabrication processes used for conventional DFB lasers, those based on laterally coupled gratings offer advantages such as regrowth-free fabrication and the associated flexibility in design. The grating can be simultaneously lithographically patterned and etched along with the ridge waveguide, significantly simplifying the device manufacturing process. The regrowth-free approach enables Al-containing epitaxial layers to be used, as there is no exposure of surfaces containing Al, which can oxidize and cause problems during epitaxial regrowth [9]. The results presented in this report suggest that our device could be used as a practical compact, stable, solid-state laser source for generating THz radiation using a photoconductive antenna [3] or nonlinear optical crystal [10].

A schematic of the fabricated device along with its dimensions is shown in Fig. 1(a). The device comprises an EAM section (30 μm), a DFB section (600 μm) with an electrical isolation slot (20 μm) between them. The ridge waveguide is 2.5 μm wide and 1.92 μm high, and the effective index of the guided mode is estimated, using numerical simulation, to be 3.20.

The epitaxial structure used for the device is based in the AlGanAs/InP material system and contains five active QWs and six quantum barriers (QB), and was previously in [11]. The EAM section, the HR coating on its output facet, and the DFB gratings form a cavity that is resonant at both DFB wavelengths. This cavity is used to enhance coupling between the two longitudinal modes, to improve phase locking, and to stabilize the mode beating frequency through the mechanism of FWM in the EAM [12]. The DFB laser has a cavity length of 600 μm. The gratings are of first-order with a 50% duty cycle and formed by etching 0.6-μm recesses into the sidewalls of the waveguide, as shown in Fig. 1(b). The periods of the gratings on each side of the ridge are 244 nm (λ1) and 245 nm (λ2), which select Bragg wavelengths of λ1 (1561.60 nm) and λ2 (1568.3 nm), respectively. The separation of the wavelengths is 6.70 nm, and the corresponding beating frequency is 820 GHz. Quarter
wavelength shifts were inserted at the middle of the DFB laser gratings to ensure each line oscillated in a single longitudinal mode [see Fig. 1(b)]. The coupling coefficient \( \kappa \) for devices with identical gratings on both sides of the ridge was measured to be approximately 80 cm\(^{-1}\) using the sub-threshold spectral fitting method. The 20-μm-long electrical isolation section between the DFB and EAM sections is formed by removing the semiconductor contact layer.

The device fabrication processes are similar to those described in [13], i.e., negative tone Hydrogen Silsequioxane (HSQ) was used as an e-beam lithography resist and reactive ion etching (RIE) dry etching hard mask, as well as a material for planarizing the 1.92-μm-high ridge waveguide and gratings [see Fig. 1(c)] [14]. As can be seen in Fig. 1(b), the mask transfer of the grating into the upper cladding layers is excellent, with good sidewall verticality, and little RIE lag at the foot of the gratings. As a final step, the sample was cleaved into individual laser bars with the facets at the DFB end of the device anti-reflection (AR) coated (≤0.05%) and the EAM facets high-reflection (HR) coated (92%). The devices were mounted epilayer-up on a copper heat sink on a Peltier cooler. The heat sink temperature was set at 20°C, and the devices were tested under CW conditions.

Figure 2 shows typical light-DFB current (\( L - I_{\text{DFB}} \)) characteristics from the DFB output side with different reverse bias voltages (\( V_{\text{EAM}} \)) applied to the EAM. The threshold current and output facet slope efficiency with a 0 V applied to the EAM section were 18 mA (1.2 kA/cm\(^2\)) and 14.7% W/A, respectively, values that are comparable to those of traditional molecular beam epitaxy (MBE) grown, buried ridge structure, AlGaInAs/InP DFB lasers [15]. When the EAM reverse voltage was increased from 0 to −2.5 V, the threshold current was unchanged, but the slope efficiency reduced as a result of increased absorption. With further increases of the EAM reverse voltage, the DFB laser became optically isolated from the HR reflector and the slope efficiency increased, with the threshold current still unchanged. This indicates that the DFB laser was working as an independent cavity, and the partitioning electrical slot prevented electrical coupling between the DFB and EAM sections.

A beating signal was observed when the DFB section was forward biased, and the EAM section was either left floating or had a reverse bias applied. For the reverse voltage applied to the EAM section in the range −1.0 V ≤ \( V_{\text{EAM}} \) ≤ −0.3 V, the beating signal was more stable, and the autocorrelation (AC) used to observe and monitor the pulse train indicated strong coherence. This is ascribed to FWM in the EAM [12] maintaining a good phase relationship between the two fundamental modes. The DFB wavelengths \( \lambda_1 \) and \( \lambda_2 \) and their spacing were accurately determined by \( \Delta \lambda_1 \) and \( \Delta \lambda_2 \), respectively. The temperature-tuning coefficient of \( \lambda_1 \) and \( \lambda_2 \) was <0.06 nm/K in the range 20°C–70°C, and so the mode spacing was in effect independent of temperature.

Stable beating over a wide range of electrical drive parameters is also a key feature of this laser, with stable THz mode beating observed for −1.0 V ≤ \( V_{\text{EAM}} \) ≤ −0.3 V and 60 mA ≤ \( I_{\text{DFB}} \) ≤ 110 mA. For −0.3 V < \( V_{\text{EAM}} \) ≤ 0 V and −2.0 V ≤ \( V_{\text{EAM}} \) < −1.0 V, the beating signal was less clear, and coherence was poor for \( V_{\text{EAM}} < −2.0 \) V. These results confirmed the importance of FWM in the EAM section—in the bias range −1.0 V ≤ \( V_{\text{EAM}} \) ≤ −0.3 V, increasingly strong mixing took place, similarly to [12]. As the bias voltage was made more negative than −1.5 V, the absorption of the EAM was so large and the cavity Q so low, the HR was effectively isolated from the DFB section, the modes were no longer locked, and the FWM peaks were no longer visible in the optical spectrum, as discussed in more detail below.

Figure 3(a) shows a 2D optical spectral plot for the most stable beating range of \( I_{\text{DFB}} \) from 60 to 110 mA with \( V_{\text{EAM}} = −0.6 \) V. The spectrum was measured with a resolution bandwidth (RBW) of 0.07 nm. The laser shows two stable longitudinal modes with a mode spacing of
around 6.7 nm. The inclusion of a quarter wavelength shift in the middle of the cavity for each grating meant that mode-hopping was suppressed. As $I_{\text{DFB}}$ was increased, the two main wavelengths were red-shifted at the same rate of 0.04 nm/mA due to heating. The mode spacing was constant over all stable bias conditions, confirming variations in the operating wavelengths of the laser resulting from tuning the DFB current do not compromise the beat tone.

Due to the high repetition frequency of the beat signal, it was not possible to perform a direct measurement of the radio-frequency (RF) characteristics. However, we were able to infer these characteristics by using the well-known coherent heterodyne technique to measure the optical linewidth of individual modes when the laser was driven to operate over ideal beating conditions. The experimental RF spectra can be approximated as having a Lorentzian profile, which means the optical spectral linewidth primarily comes from the spontaneous emission of the intrinsic linewidth of the laser itself [16].

The technical noise, such as mechanical vibrations, temperature fluctuations, and injection current noise, can be neglected [16]. Figure 3(b) shows the measured beat mode linewidth as a function of $I_{\text{DFB}}$ for $V_{\text{EAM}} = -0.6$ V. Here, we note the trend that the beat mode linewidth reduces as $I_{\text{DFB}}$ is increased. The narrowest observed linewidth of about 700 kHz was achieved at $I_{\text{DFB}} = 100$ mA.

In contrast, a separate measurement of a counterpart single grating DFB laser emitting a single longitudinal mode fabricated in the same wafer has a typical optical linewidth of 3.5 MHz at the same current injection level. This reduction of the linewidth provides strong evidence that in the beating regime, the two modes are indeed mutually phase-locked.

The far field pattern (FFP) from the DML was measured with high resolution (0.9°). The inset in Fig. 3(b) shows the 2D FFP measured at $I_{\text{DFB}} = 100$ mA and $V_{\text{EAM}} = -0.6$ V. The beam is almost circular (34° × 35°) and is indistinguishable to that expected from the fundamental mode of the ridge waveguide, confirming both of the lasing wavelengths are in the fundamental TE mode. Moreover, when displacing an optical fiber along the transversal horizontal direction (\(\perp\)) closely approaching the DFB output facet while scanning $I_{\text{DFB}}$ and $V_{\text{EAM}}$, the measured optical spectrum is not sensitive to the fiber position.

Figure 4(a) shows the optical spectra of the DFB laser at an injection current of 100 mA with $V_{\text{EAM}} = -0.6$ V. The measured lasing modes were at wavelengths of 1562.8 (peak P1) and 1569.5 nm (peak P2), corresponding to a difference frequency of 820 GHz, with a side mode suppression ratio (SMSR) >42 dB. The values of P1 and P2 differ because of the gain spectrum of the material. The FWM sidebands at 1556.2 (peak FWM1) and 1576.3 nm (peak FWM2) can be clearly seen. The 15-dB power enhancements of the sidebands above the cavity modes indicate good phase stability between the two main modes [6]. In a practical THz system, the sidebands would not affect photomixing, as their power is, in turn, about 35 dB below the two main lasing modes.

The corresponding measured AC trace is shown in Fig. 4(b), which indicates a sinusoidal modulation with some fluctuations in the peak intensity, which are due to the finite resolution of the autocorrelator system itself. The average period of the measured emitted pulse train was 1.22 ps, which corresponds to the expected repetition frequency of 820 GHz, and is in agreement with the optical spectrum mode spacing shown in Fig. 4(a).

Figure 4(c) shows the dependence of the FWM output power on applied EAM voltage. As can be seen, FWM1 and FWM2 increased when $V_{\text{EAM}}$ was changed from 0 to $-0.6$ V, and then reduced when $V_{\text{EAM}} < -0.6$ V. The FWM signals were apparent until the bias on the EAM reached $-1.4$ V, beyond which no evidence of FWM could be seen in the optical spectrum. FWM1/P1 (the ratio of FWM1 to P1), and FWM2/P2 (the ratio of FWM2 to P2) follow the same trend. Figure 4(c) confirms the key role that the EAM plays in terms of locking the phases of the two longitudinal modes [12].

In conclusion, a laterally coupled, dual-wavelength DFB laser integrated with a nonlinear FWM cavity has been fabricated and characterized. The device emits two longitudinal modes simultaneously from within the same cavity, separated by 0.82 THz at a wavelength of around 1560 nm. The devices were fabricated using simple first-order sidewall gratings technologies, which have the advantages of eliminating crystal regrowth and allowing the AlGaNAs quaternary structure to be used in the QW active section. The surface grating eliminates the need for complex regrowth fabrication steps normally associated with DFB lasers. Due to FWM in the
resonant cavity, the device strongly favors operation in the mode-beating regime, with stable mode beating observed over a wide range of bias parameters in terms of drive current to the DFB and bias to the EAM. Compared with other reported DMLs, our laser uses a simple and reproducible fabrication technology and exhibits highly controllable and robust mode-beating operation. These laser diodes are expected to open up many opportunities for future compact THz applications.

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References

Queries

1. AU: Edits to title OK?